

[54] MICROMETER

3,608,201 9/1971 Butsch ..... D10/73 X  
4,168,575 9/1979 Sugizaki ..... 33/166 X

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[73] Assignee: Mitutoyo Mfg. Co., Ltd., Tokyo, Japan

[\*\*] Term: 14 Years

[21] Appl. No.: 83,626

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[51] Int. Cl. .... D10-04

[52] U.S. Cl. .... D10/73

[58] Field of Search ..... D10/73; 33/166

[56] References Cited

U.S. PATENT DOCUMENTS

- D. 198,710 7/1964 Himmelsbach ..... D10/73
- D. 239,704 4/1976 Morgan ..... D10/73
- D. 253,689 12/1979 Tanada ..... D10/73
- D. 254,655 4/1980 Brickwood ..... D10/73

OTHER PUBLICATIONS

*Alina Catalog No. IN-200-2 Instrument Div., p. 7-Diac Micrometer at center.*

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Attorney, Agent, or Firm—Koda and Androlia*

[57] CLAIM

The ornamental design for a micrometer, substantially as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a micrometer showing our new design;  
FIG. 2 is a front elevational view thereof;  
FIG. 3 is a top plan view thereof;  
FIG. 4 is a rear elevational view thereof;  
FIG. 5 is a left-side elevational view thereof;  
FIG. 6 is a right-side elevational view thereof; and  
FIG. 7 is a bottom plan view thereof.

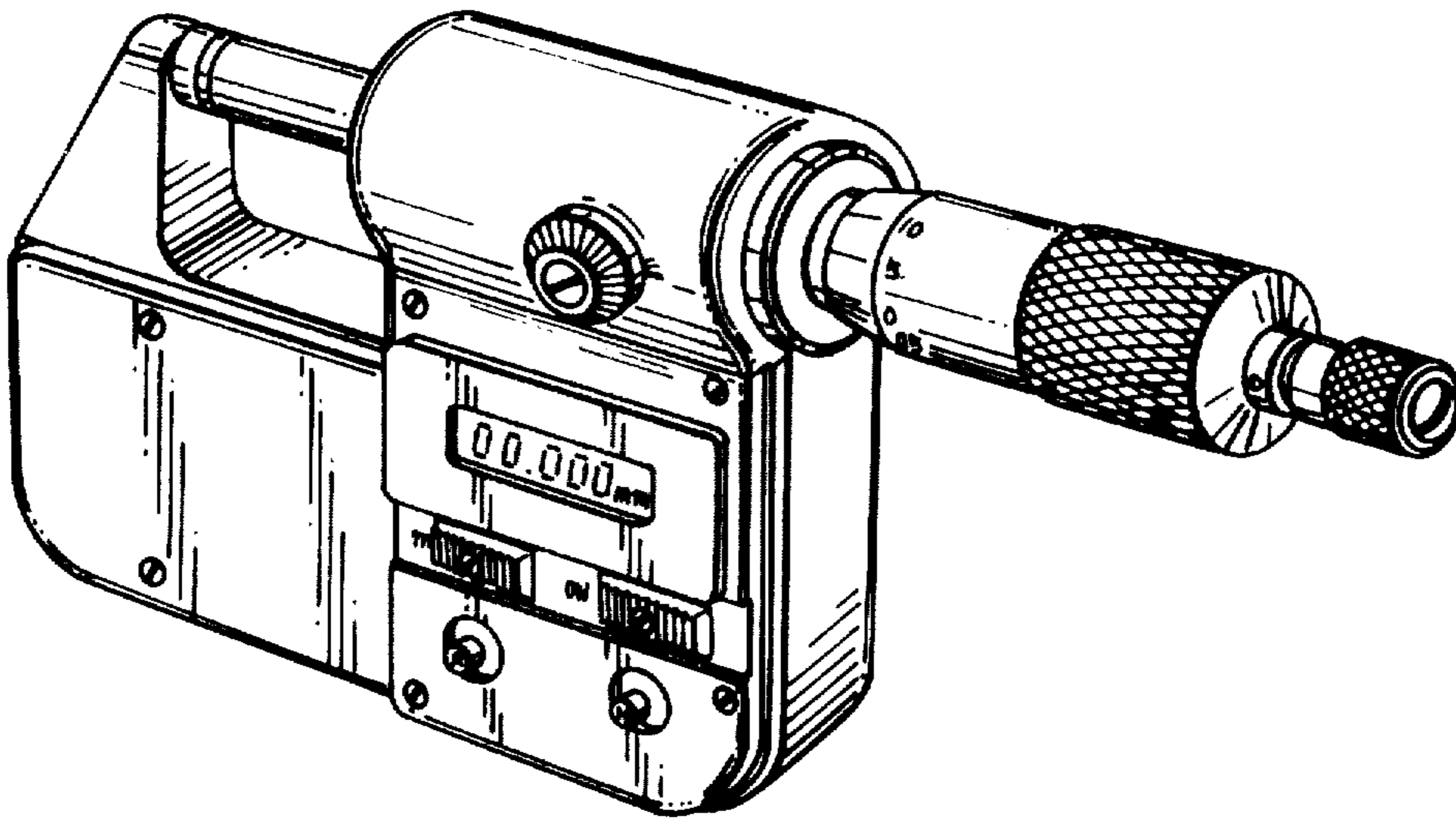


FIG. 1

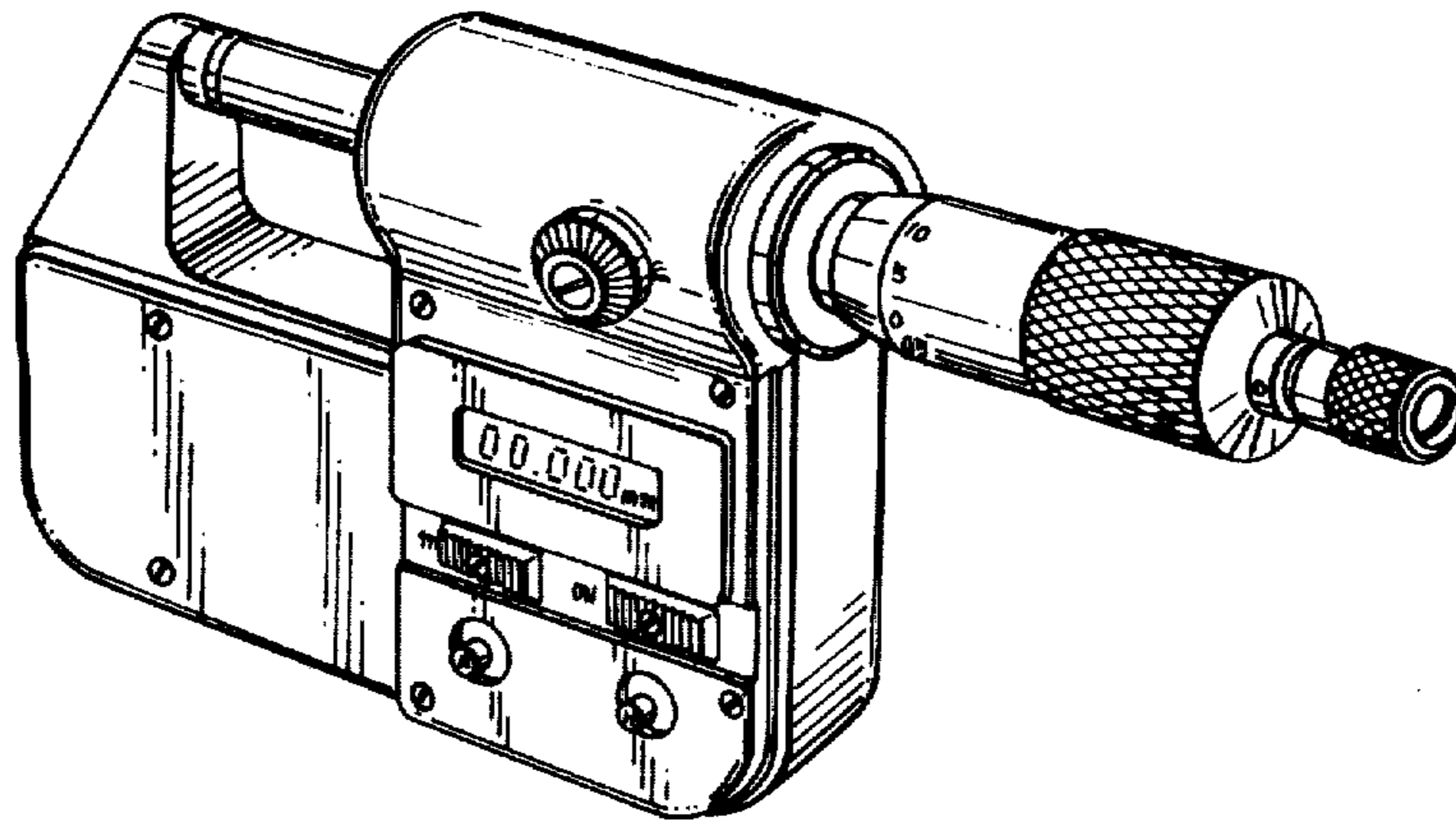


FIG. 2

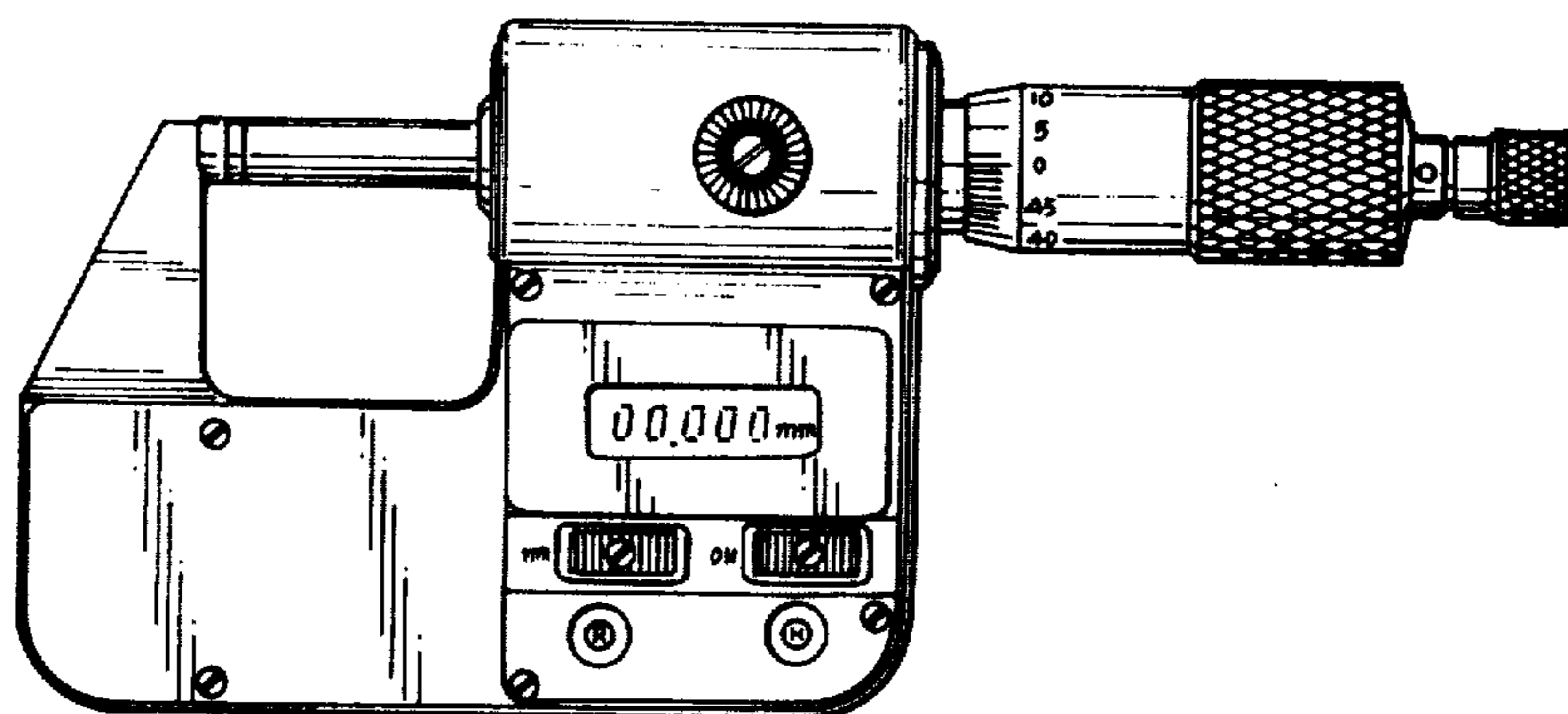


FIG. 3

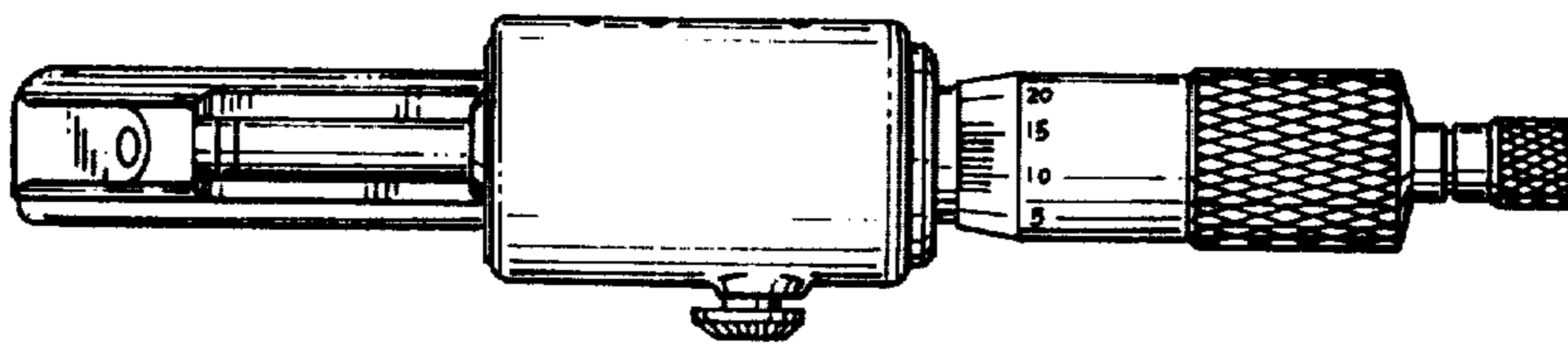


FIG. 4

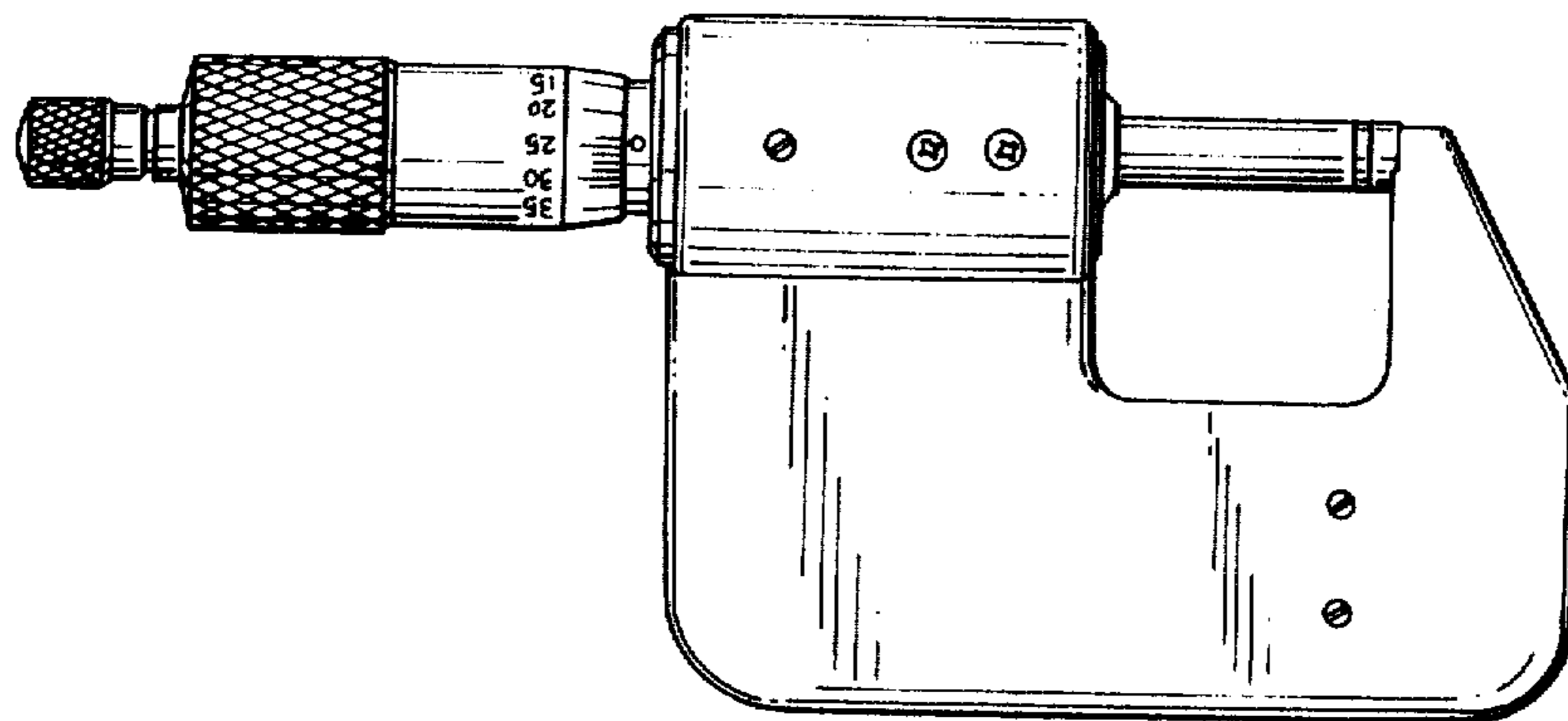


FIG. 5

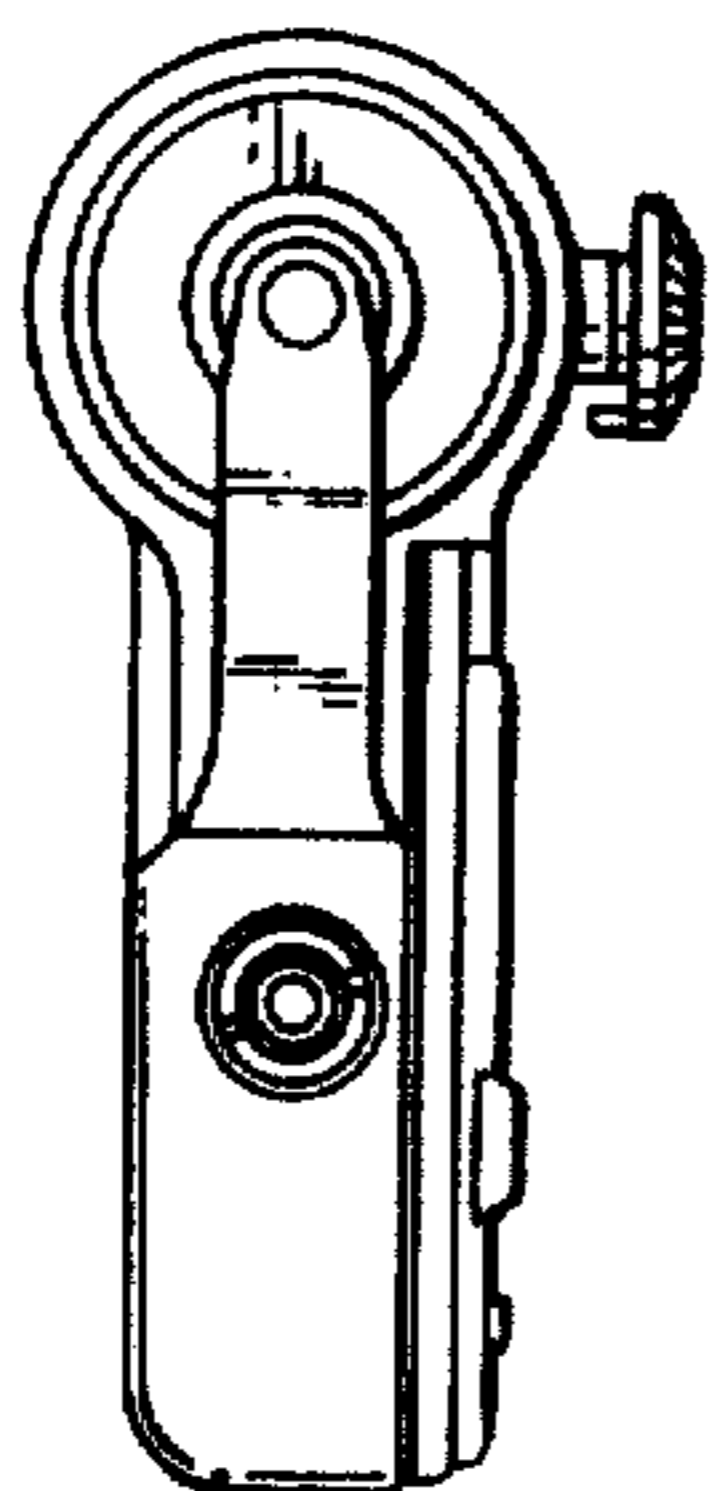


FIG. 6

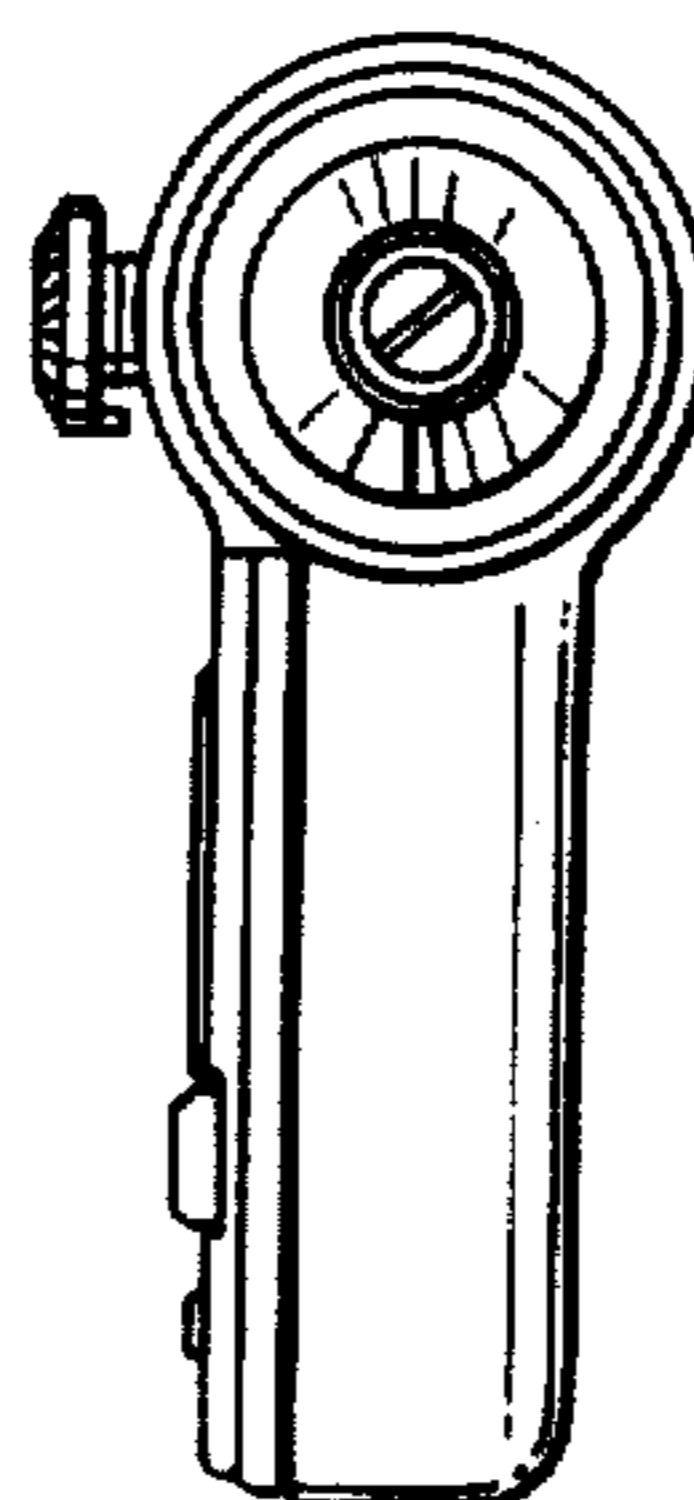


FIG. 7

